

# Anisotropic Etching Patterns in 2D $\text{Cr}_5\text{Te}_8$ Nanosheets and Their Arduous Saturation Magnetization

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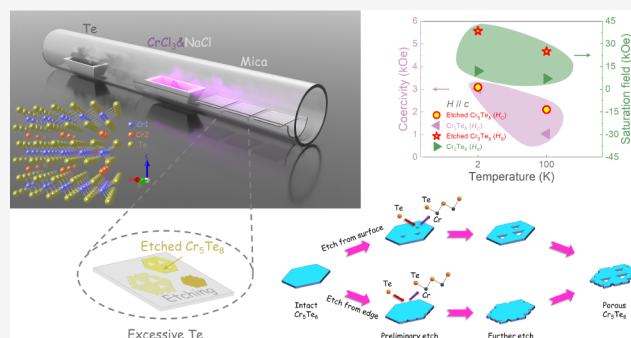
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**ABSTRACT:** Although 2D self-intercalated  $\text{Cr}_5\text{Te}_8$  has been successfully synthesized via chemical vapor deposition (CVD), its etching behavior remains largely unexplored. Etching, as the inverse process of material growth, is essential for understanding growth mechanisms and fabricating nanosheet patterns. Herein, we explore the anisotropic etching of 2D  $\text{Cr}_5\text{Te}_8$  assisted by an excess Te supply. The etching process initiates from both the surface and the edge, creating distinct holes and nanoribbons with triangular or hexagonal shapes. To the best of our knowledge, this is the first report on controllable anisotropic etching patterns in 2D  $\text{Cr}_5\text{Te}_8$ . Furthermore, magnetic measurements reveal ferromagnetism in the etched nanosheets with a Curie temperature ( $T_C$ ) of 164 K, slightly lower than that of the unetched nanosheets. The etched nanosheets exhibit an enhanced saturated magnetic field of 38.5 kOe, approximately 3.2 times that of the unetched nanosheets. This enhancement in the saturated magnetic field is attributed to the pattern-induced strengthening of the reentrant stray field. This study offers a new direction for preparing patterned 2D materials and opens a novel avenue for modulating 2D magnetism.



## INTRODUCTION

Due to their exceptional electrical,<sup>1,2</sup> photoelectrical,<sup>3,4</sup> and magnetic properties,<sup>5–7</sup> two-dimensional (2D) magnetic materials have attracted considerable attention for their potential in diverse applications. Among these, self-intercalated 2D chromium telluride ( $\text{Cr}_x\text{Te}_y$ ) stands out due to its diverse thickness-dependent magnetism and self-intercalated phases, offering significant prospects for fundamental studies and spintronic device applications.<sup>8–20</sup> Notably, the 2D  $\text{Cr}_5\text{Te}_8$  nanosheet has been reported to exhibit ferromagnetism with pronounced out-of-plane spin polarization, facilitated by strong interlayer magnetic coupling.<sup>21–29</sup> Additionally, magnetic force microscopy (MFM) has revealed magnetic bubbles and thickness-dependent labyrinthine domains in  $\text{Cr}_5\text{Te}_8$  nanosheets, underscoring the transition in the dominant role of ferromagnetism from dipolar interactions to magnetic anisotropy in the 2D regime.<sup>21</sup>

Despite the successful synthesis of 2D  $\text{Cr}_5\text{Te}_8$  via chemical vapor deposition (CVD), the growth mechanism of self-intercalated 2D  $\text{Cr}_5\text{Te}_8$  remains incompletely understood.<sup>21–26</sup> From a microscopic perspective, etching is commonly perceived as the inverse process of growth.<sup>30–33</sup> Hence, understanding the etching process of materials is essential for gaining insight into their growth mechanisms. Furthermore, etching is widely recognized as a top-down approach for

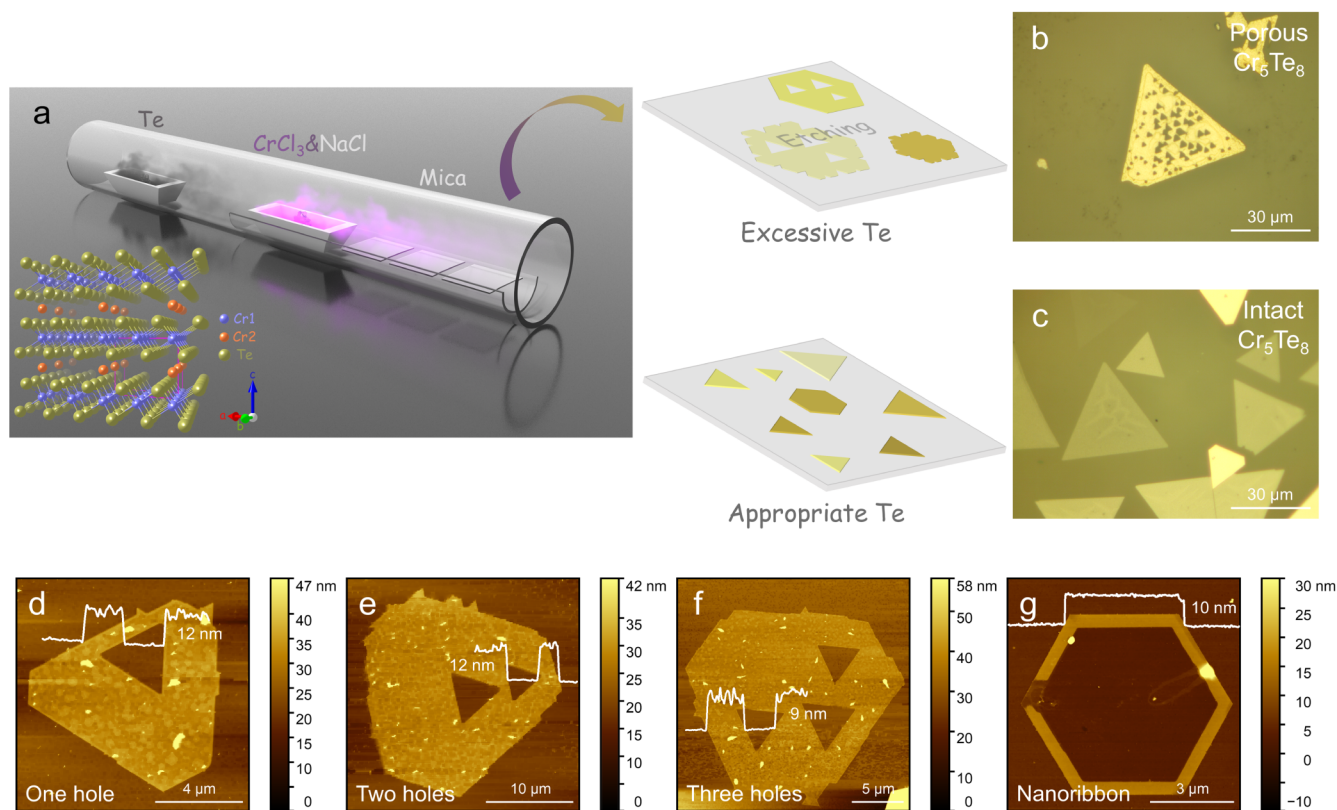
constructing specific patterns, potentially leading to the emergence of unique properties due to symmetry alterations in the material.<sup>32</sup> Previous research on 2D material etching has focused on graphene,<sup>34</sup> hexagonal boron nitride (h-BN),<sup>35</sup> transition metal dichalcogenides (TMDs),<sup>32,36,37</sup> and metal monochalcogenides,<sup>30</sup> while the self-intercalated structure of  $\text{Cr}_5\text{Te}_8$ , where intercalated Cr atoms chemically bond with Te atoms, suggests distinct growth and etching mechanisms compared to these materials. However, research on the etching behavior of self-intercalated materials during the CVD process is still in its nascent stages, lacking both theoretical guidance and experimental evidence.<sup>31,33</sup> Therefore, investigating the etching behavior of 2D  $\text{Cr}_5\text{Te}_8$  is crucial for a profound understanding of the etching and growth mechanisms of self-intercalated materials, as well as for tuning emergent 2D magnetism.

Herein, we fabricated  $\text{Cr}_5\text{Te}_8$  nanosheets with anisotropic etching holes and nanoribbons. Under excess Te supply,

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**Figure 1.** Growth method and morphology in etched  $\text{Cr}_5\text{Te}_8$ . (a) Schematic diagram illustrating the one-step CVD growth of etched  $\text{Cr}_5\text{Te}_8$  nanosheets. The inset depicts the crystal structure (side view) of  $\text{Cr}_5\text{Te}_8$ . (b,c) Typical OM images of  $\text{Cr}_5\text{Te}_8$  grown on mica substrates with excessive (b) and appropriate (c)  $\text{Te}$  powder. (d–f) Typical AFM topographies of etched  $\text{Cr}_5\text{Te}_8$  nanosheets with 1 hole (d), 2 holes (e), and 3 holes (f), respectively. (g) AFM topography of the resulting  $\text{Cr}_5\text{Te}_8$  nanoribbons after etching.

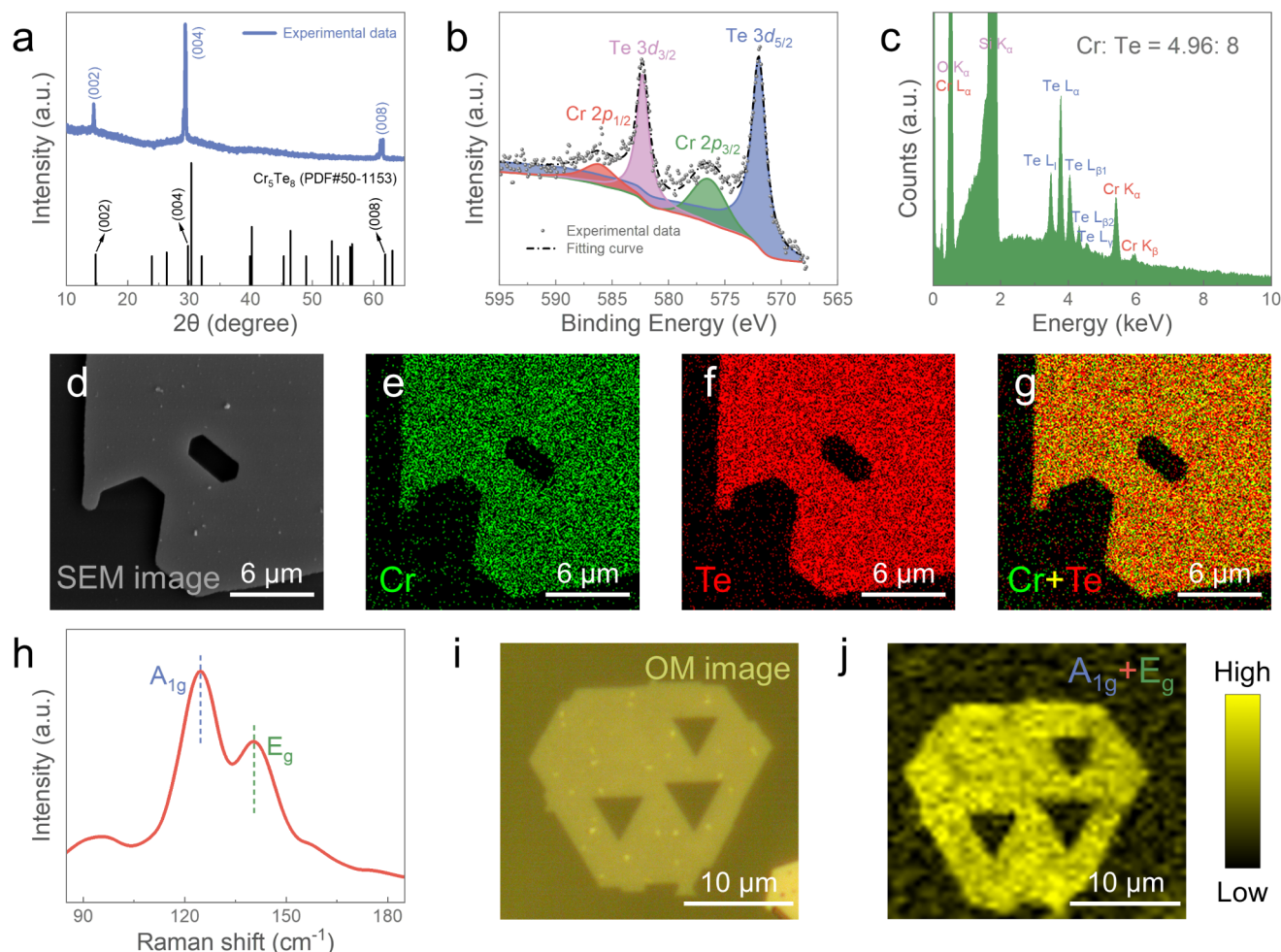
$\text{Cr}_5\text{Te}_8$  nanosheets undergo anisotropic etching, resulting in well-defined patterns, such as triangular and hexagonal holes on the nanosheets. Furthermore, by precisely adjusting the  $\text{Te}$  source,  $\text{Cr}_5\text{Te}_8$  nanosheets were etched into nanoribbons. The etching process was initiated from the surface and the edge. Although a similar etching process by excess chalcogen precursors was reported in the CVD growth of  $\text{MoS}_2$  nanosheets, excess sulfur etching only reduced edge length and did not form pattern structure.<sup>36</sup> To the best of our knowledge, this is the first experimental demonstration of controllable etching in 2D  $\text{Cr}_5\text{Te}_8$  nanosheets. Optical microscopy (OM), atomic force microscopy (AFM), X-ray diffraction (XRD), X-ray photoelectron spectroscopy (XPS), scanning electron microscopy (SEM) coupled with energy-dispersive spectroscopy (EDS), and Raman spectroscopy confirmed the high crystallinity, accurate composition, and structure of etched  $\text{Cr}_5\text{Te}_8$  nanosheets. Additionally, the magnetic property measurement system (MPMS) revealed that etched  $\text{Cr}_5\text{Te}_8$  nanosheets exhibit ferromagnetism with a Curie temperature ( $T_C$ ) of 164 K. Notably, these etched nanosheets demonstrated an enhanced saturated magnetic field of up to 38.5 kOe, possibly attributed to the increased edge proportion, which strengthens the reentrant stray field of the saturated magnetic domains. This study provides crucial insights into the multifaceted etching behavior of  $\text{Cr}_5\text{Te}_8$ , offering a novel approach for modulating the magnetism of 2D materials and serving as an important experimental reference for understanding the etching behavior and emergent properties of other self-intercalated materials during the CVD process.

## MATERIAL AND METHODS

**Growth of Etched  $\text{Cr}_5\text{Te}_8$ .** The growth of etched  $\text{Cr}_5\text{Te}_8$  nanosheets was conducted in a dual-zone tubular furnace equipped with a 1-in. diameter quartz tube by atmospheric pressure CVD.  $\text{Te}$  powder (0.5–1 g, Alfa Aesar, 99.99% purity) was positioned in the first temperature zone (700 °C), while a mixture of  $\text{CrCl}_3$  (4 mg, Alfa Aesar, 99.9% purity) as the Cr precursor and  $\text{NaCl}$  (1.5 mg, Alfa Aesar, 99.99% purity) as the cosolvent was placed in the second temperature zone (850 °C) inside the quartz tube. Freshly cleaved fluorophlogopite mica ( $\text{KMg}_3\text{AlSi}_3\text{O}_{10}\text{F}_2$ ) substrates were positioned adjacent to the  $\text{CrCl}_3$  powder. Prior to growth, the quartz tube underwent vacuuming and purging with Ar gas twice to eliminate oxygen and moisture residues. A mixture of 145 sccm Ar and 5 sccm  $\text{H}_2$  was used to transport vapor species to the substrates, and the growth process lasted for about 10 min.

**Transfer of Etched  $\text{Cr}_5\text{Te}_8$ .** Etched  $\text{Cr}_5\text{Te}_8$  nanosheets on mica were transferred to  $\text{SiO}_2/\text{Si}$  substrates by using polystyrene (PS) as a medium for further characterization. Briefly, the etched  $\text{Cr}_5\text{Te}_8$  grown on mica was coated with a PS solution and baked on a hot plate at 60 °C for 30 min to enhance adhesion between the nanosheets and PS. Subsequently, the PS/etched  $\text{Cr}_5\text{Te}_8/\text{mica}$  was immersed in deionized water to separate the PS/etched  $\text{Cr}_5\text{Te}_8$  from the mica. The PS/etched  $\text{Cr}_5\text{Te}_8$  was then transferred onto  $\text{SiO}_2/\text{Si}$  substrates and baked again at 60 °C for 30 min. Finally, the PS was removed by using anisole.

**Characterization of Etched  $\text{Cr}_5\text{Te}_8$ .** The morphology and thickness of the etched  $\text{Cr}_5\text{Te}_8$  nanosheets were characterized using OM (6XB-PC, Shang Guang) and AFM (Dimension ICON, Bruker). The phase structure of the etched  $\text{Cr}_5\text{Te}_8$  was analyzed by XRD (D8 ADVANCE, Bruker). XPS (ESCALAB 250Xi, Thermo Fisher Scientific) was used to analyze the binding energies. The elemental composition and distribution were evaluated using SEM (NOVA NANOSEM450, FEI) equipped with EDS (X-MaxN 50 mm<sup>2</sup>, Oxford



**Figure 2.** Structural and compositional characterization of etched  $\text{Cr}_5\text{Te}_8$ . (a) XRD patterns of etched  $\text{Cr}_5\text{Te}_8$  nanosheets transferred to the  $\text{SiO}_2/\text{Si}$  substrate (top) and the standard  $\text{Cr}_5\text{Te}_8$  crystal from the PDF card (bottom). (b) XPS of etched  $\text{Cr}_5\text{Te}_8$  nanosheets. (c) EDS of etched  $\text{Cr}_5\text{Te}_8$  nanosheets. (d–g) SEM image (d) and the corresponding EDS mapping of the Cr element (e), Te element (f), and an overlay of Cr and Te elements (g) of a representative etched  $\text{Cr}_5\text{Te}_8$  nanosheet. (h) Raman spectrum of an individual etched  $\text{Cr}_5\text{Te}_8$  nanosheet. (i,j) OM image (i) and the corresponding Raman mapping of an overlay of  $A_{1g}$  and  $E_g$  modes (j) of a representative etched  $\text{Cr}_5\text{Te}_8$  nanosheet.

Instruments). Raman spectroscopy was employed to identify vibrational modes using confocal Raman microscopy (alpha300 R, WITec).

The  $T_C$  and magnetic hysteresis loops were measured by MPMS (MPMS3, Quantum Design), which was used to measure the magnetic properties of etched  $\text{Cr}_5\text{Te}_8$  on mica, including saturated magnetic field values. The temperature-dependent magnetic moments ( $M-T$ ) were measured between 1.8 and 400 K through zero-field cooling (ZFC) and field cooling (FC) processes with an additional magnetic field of 1 kOe perpendicular to the  $ab$ -plane. Field-dependent magnetizations ( $M-H$ ) were carried out with the applied field ranging from  $-70,000$  Oe to  $+70,000$  Oe perpendicular to the  $ab$ -plane at 2 and 100 K.

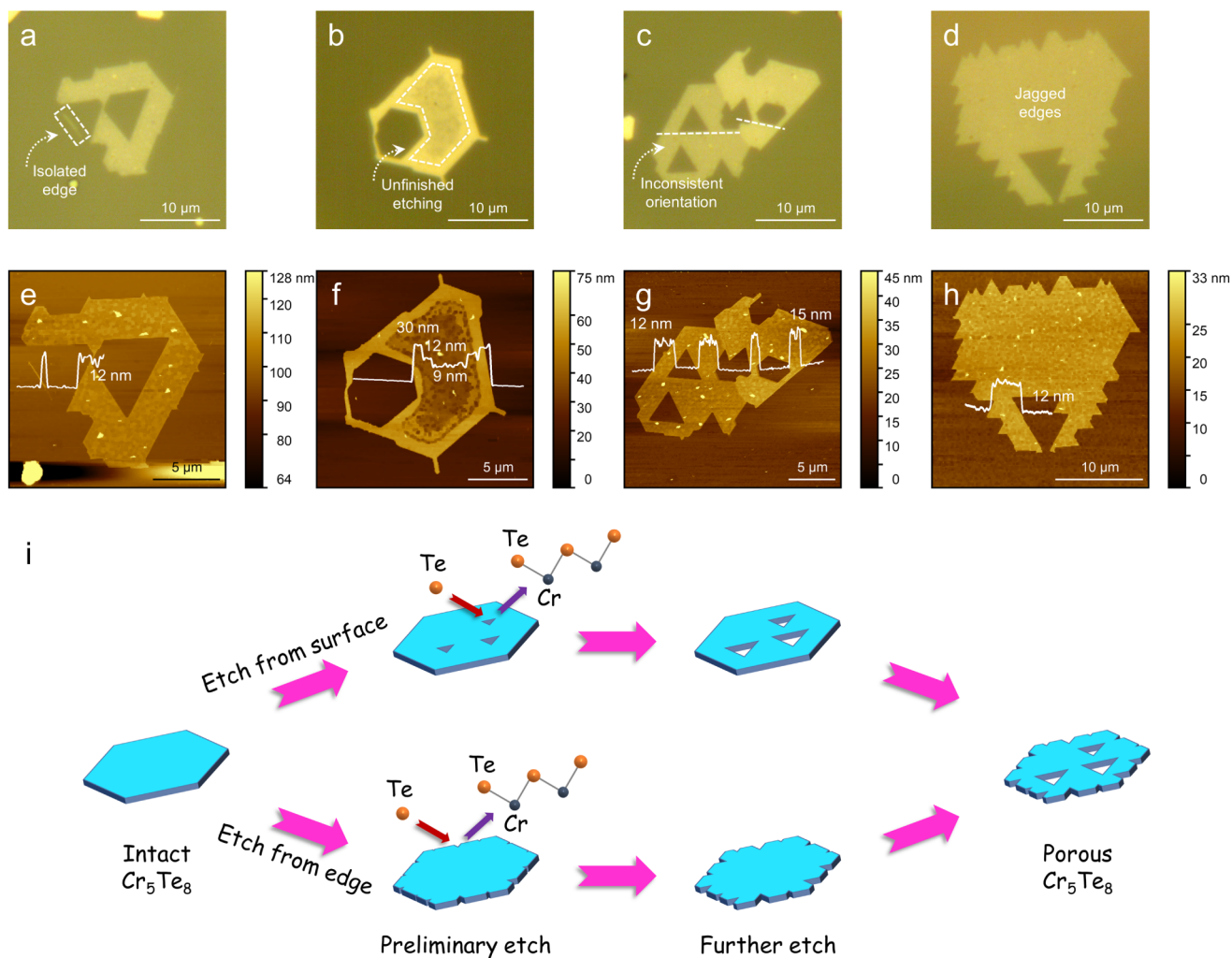
## RESULTS AND DISCUSSION

The one-step CVD growth process used to synthesize 2D  $\text{Cr}_5\text{Te}_8$  nanosheets with etched patterns is depicted in Figure 1a. Within a dual-zone tubular furnace, Te powder is positioned in the first temperature zone, while a mixture of  $\text{CrCl}_3$  and NaCl powders is placed in the second temperature zone inside the quartz tube. The mica substrates are positioned in proximity to the mixture of  $\text{CrCl}_3$  and NaCl powders. Etching and growth are complementary processes. The two processes compete during the growth of the 2D crystal.<sup>30</sup>

Therefore, the dominant role between etching and growth changes with the amount of Te precursors, which shifts from growth to etching as the amount of Te precursors increases. According to the amount of Te precursors, we define the amount of Te powder and its corresponding vapor temperature for unetched  $\text{Cr}_5\text{Te}_8$  nanosheet synthesis as the “appropriate Te supply condition”, for example 400 mg of Te powder and 550 °C (vapor temperature of Te) in our previous report.<sup>21</sup> The “excessive Te supply condition” is defined as a Te powder quantity ranging from 0.5 to 1 g and a vapor temperature of 700 °C.

Under an excess Te supply, etching dominates.  $\text{Cr}_5\text{Te}_8$  nanosheets undergo anisotropic etching, resulting in well-defined etched patterns characterized by triangular and hexagonal holes. Excess Te likely etches  $\text{Cr}_5\text{Te}_8$  flakes by reacting with Cr atoms to create low-melting-point Cr–Te compounds, which then detach from the carrier gas. Although no similar anisotropic etching effect with excess chalcogen precursors has been reported in self-intercalated materials, a similar etching structure was observed in the CVD growth of  $\text{MoS}_2$  with excess sulfur, which changed edge lengths and morphological structures.<sup>36</sup> Conversely, under an appropriate Te supply, unetched  $\text{Cr}_5\text{Te}_8$  nanosheets are formed.<sup>21</sup> Typical





**Figure 3.** Etching mechanism of  $\text{Cr}_5\text{Te}_8$ . (a–d) OM images of  $\text{Cr}_5\text{Te}_8$  with distinctive etching patterns. (e–h) AFM topographies corresponding to (a–d). (i) Schematic diagram of two etching pathways in  $\text{Cr}_5\text{Te}_8$ : initiating from the surface and initiating from the edge.

OM images of etched  $\text{Cr}_5\text{Te}_8$  and pristine  $\text{Cr}_5\text{Te}_8$  are presented in Figure 1b,c, respectively.<sup>21</sup>

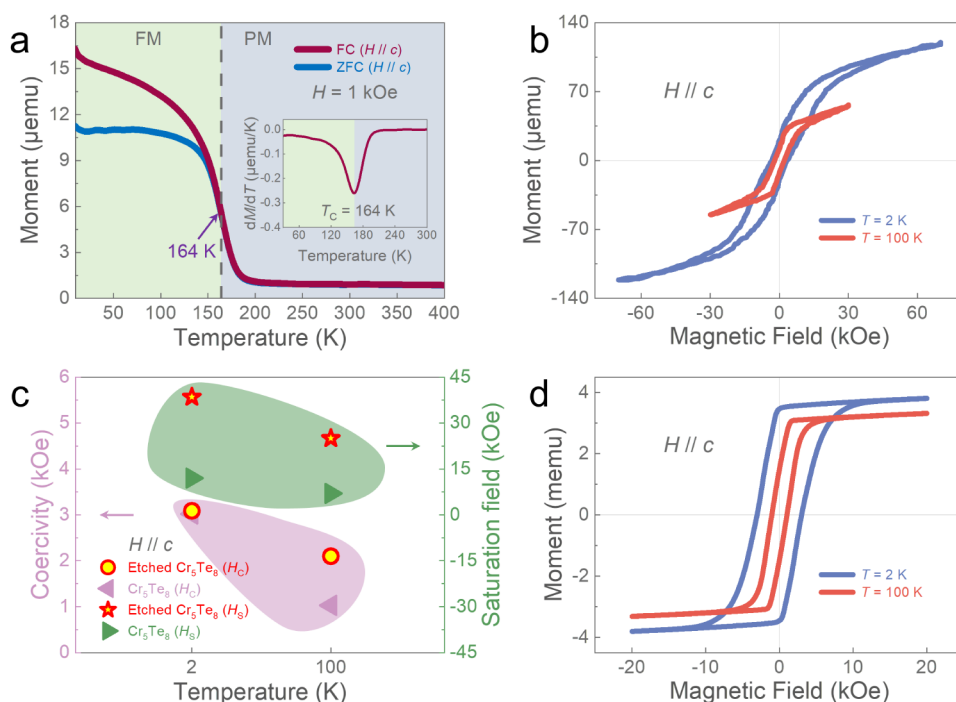
To further verify the anisotropic etching of  $\text{Cr}_5\text{Te}_8$  nanosheets, AFM characterization was employed on the etched  $\text{Cr}_5\text{Te}_8$ . Typical AFM topographies of 2D  $\text{Cr}_5\text{Te}_8$  with etched patterns are presented in Figure 1d–g. The etched hole patterns exhibit directional triangular or hexagonal shapes with the hole edges aligned with the nanosheet edges. These distinct hole geometries directly validate the anisotropic nature of the etching process. Figure 1d–f depicts etched  $\text{Cr}_5\text{Te}_8$  with varying hole densities. These topographies indicate that the nanosheet thicknesses are between 9 and 12 nm. Additionally, line profiles clearly confirm the formation of holes after the etching of  $\text{Cr}_5\text{Te}_8$ . Furthermore, the etching is related to the amount of Te. When the amount of Te increases, the etching effect is enhanced. The 1 g Te precursor results in more extensive etching of  $\text{Cr}_5\text{Te}_8$ . Figure 1g illustrates hexagonal ring-shaped, 10 nm thick  $\text{Cr}_5\text{Te}_8$  nanoribbons approximately 1.5  $\mu\text{m}$  in length and 180 nm in width after deep etching.

To confirm the crystal structure and composition of  $\text{Cr}_5\text{Te}_8$  with etched patterns, comprehensive characterizations were conducted after the etched  $\text{Cr}_5\text{Te}_8$  on mica was transferred to  $\text{SiO}_2/\text{Si}$  substrates to eliminate interference from the mica. In

Figure 2a, XRD diffraction peaks at  $14.4^\circ$ ,  $29.3^\circ$ , and  $61.5^\circ$  correspond to the (002), (004), and (008) diffraction planes, consistent with the standard PDF card of  $\text{Cr}_5\text{Te}_8$  (PDF#50-1153).<sup>28,29</sup> This alignment affirms the structural accuracy of the as-grown 2D  $\text{Cr}_5\text{Te}_8$  with etched patterns. Only (00X) peaks are observed in the XRD pattern, indicating that the surface of the etched  $\text{Cr}_5\text{Te}_8$  is parallel to the  $ab$ -plane. The XPS spectrum exhibits binding energy peaks at 576.39 eV (Cr  $2p_{3/2}$ ), 586.09 eV (Cr  $2p_{1/2}$ ), 571.98 eV (Te  $3d_{5/2}$ ), and 582.28 eV (Te  $3d_{3/2}$ ), as shown in Figure 2b. These peaks indicate  $\text{Cr}^{3.2+}$  and  $\text{Te}^{2-}$  states, determined using the charge potential model (CPM) and referencing standard data from the XPS handbook, which align with the valence states of  $\text{Cr}_5\text{Te}_8$  crystals.<sup>21,22</sup>

EDS analysis of etched  $\text{Cr}_5\text{Te}_8$  reveals an atomic ratio of Cr to Te approximately equal to 4.96:8, in good agreement with the stoichiometric ratio of  $\text{Cr}_5\text{Te}_8$ , as shown in Figure 2c. The SEM image and corresponding EDS mappings (Figure 2d–g) show clear contrasts between darkened holes and brightened nanosheets, confirming the formation of etched holes. The uniform color distribution of the nanosheets indicates the spatial uniformity of Cr and Te components, affirming the high quality of the etched  $\text{Cr}_5\text{Te}_8$ . Raman spectrum analysis on an individual  $\text{Cr}_5\text{Te}_8$  nanosheet with etched patterns, as shown in





**Figure 4.** Ferromagnetism of the etched-pattern  $\text{Cr}_5\text{Te}_8$ . (a)  $M$ - $T$  curves of both the FC process (red line) and ZFC process (blue line) under an external field of 1 kOe perpendicular to the  $ab$ -plane. The inset displays the first-order derivative of  $M$  with respect to  $T$  to determine the  $T_C$  of etched  $\text{Cr}_5\text{Te}_8$ . (b, d)  $M$ - $H$  curves of etched  $\text{Cr}_5\text{Te}_8$  (b) and intact  $\text{Cr}_5\text{Te}_8$  (d) with the magnetic field perpendicular to the  $ab$ -plane at different temperatures. (c) Temperature-dependent coercivity and saturation field for etched  $\text{Cr}_5\text{Te}_8$  and intact  $\text{Cr}_5\text{Te}_8$  with the magnetic field perpendicular to the  $ab$ -plane.

Figure 2h, displays prominent peaks at  $125\text{ cm}^{-1}$  and  $140\text{ cm}^{-1}$ , corresponding to  $A_{1g}$  and  $E_g$  modes,<sup>21–26</sup> further confirming the crystallinity of etched  $\text{Cr}_5\text{Te}_8$ . As shown in Figure 2i,j, the OM image and corresponding Raman mappings provide additional evidence of the presence of holes in the  $\text{Cr}_5\text{Te}_8$  nanosheets.

Furthermore, the unetched  $\text{Cr}_5\text{Te}_8$  nanosheets were reported in our previous work,<sup>21</sup> and their composition and structural characteristics are identical to those of the etched nanosheets. Therefore, we conclude that the only difference between etched and unetched  $\text{Cr}_5\text{Te}_8$  lies in the morphology, with the etched samples exhibiting no detectable defect states within the resolution of our measurements. In summary, the etched  $\text{Cr}_5\text{Te}_8$  nanosheets retain the same quality, precise composition, and crystal structure as the unetched  $\text{Cr}_5\text{Te}_8$ . These findings provide an excellent opportunity for further investigations into the etching mechanism and its impact on the 2D magnetism of  $\text{Cr}_5\text{Te}_8$ .

To investigate the etching mechanism of  $\text{Cr}_5\text{Te}_8$ , we performed OM and AFM measurements on additional  $\text{Cr}_5\text{Te}_8$  nanosheets with etched patterns on mica. Figure 3a–d presents OM images of  $\text{Cr}_5\text{Te}_8$  with distinctly different etching patterns. The corresponding AFM topographies are shown in Figure 3e–h. In Figure 3a,e, the etching leaves an isolated-edge structure on  $\text{Cr}_5\text{Te}_8$ , indicating that the holes are indeed formed through etching rather than by separately assembling different  $\text{Cr}_5\text{Te}_8$  molecules. Figure 3b,f shows the etched  $\text{Cr}_5\text{Te}_8$  nanosheets with multiple “steps”, suggesting that the etching process can start from the center of the nanosheet and gradually propagate outward. In Figure 3c,g, two  $\text{Cr}_5\text{Te}_8$  nanosheets with different orientations are merged, and each hole’s edge is parallel to the edge of its respective nanosheet. This orientation indicates that the anisotropy of the

etched holes is only related to the crystal orientation of  $\text{Cr}_5\text{Te}_8$ . The shape of the etched  $\text{Cr}_5\text{Te}_8$  nanosheet in Figure 3d,h is distinctly different from those shown in Figure 3a–c. The nanosheet’s edge displays numerous serrations, suggesting that the etching process can initiate from both the surface and the edge of nanosheets. Additionally, in Figure 3a–h, various etched hole shapes, such as triangles and hexagons, are observed. These different etching patterns may result from the atomic termination differences at the hole edges, arising from the competition between the Te atom detachment rate and the Cr atom detachment rate during the etching process, similar to the etching of other 2D materials such as  $\text{MoS}_2$ , where triangular and hexagonal holes are characterized by edges terminated by different atoms.<sup>37</sup>

During the etching process of  $\text{Cr}_5\text{Te}_8$ , the freshly grown  $\text{Cr}_5\text{Te}_8$  nanosheets undergo a desorption process in the presence of excess Te, leading to the formation of lower-melting-point Cr–Te compounds, which subsequently detach from the nanosheet. Two potential etching pathways have been identified. The etching model is illustrated in Figure 3i. The etching of an entire  $\text{Cr}_5\text{Te}_8$  nanosheet can occur simultaneously along two pathways: the first involves the random formation of etching sites on the surface, followed by the etching gradually expanding outward along the crystal orientation of  $\text{Cr}_5\text{Te}_8$  from these sites; the second pathway entails direct etching from the edge inward along the crystal orientation. The concurrent progression of etching along these two pathways results in the formation of  $\text{Cr}_5\text{Te}_8$  with anisotropic hole patterns. Moreover, due to the higher atomic reactivity at the edge of  $\text{Cr}_5\text{Te}_8$  nanosheets compared to the surface, it is more likely for etching sites to form at the edges. This is consistent with the higher hole density and deeper etching observed at the edges of the nanosheets in Figure 3a–

h, as well as the increased hole density at the corners of etched MoS<sub>2</sub> flakes compared to the central regions.<sup>37</sup> These findings provide crucial insights into the multifaceted etching behavior of Cr<sub>5</sub>Te<sub>8</sub>, revealing the intricate interplay between the etching processes and the crystal anisotropy of Cr<sub>5</sub>Te<sub>8</sub>.

To investigate the impact of etching on the magnetism of Cr<sub>5</sub>Te<sub>8</sub> compared with that of pristine Cr<sub>5</sub>Te<sub>8</sub>, MPMS was used to measure the total magnetic signal of all etched nanosheets on mica. The ZFC and FC curves under an external field of 1 kOe perpendicular to the *ab*-plane are presented in Figure 4a. The magnetic moment decreases with increasing temperature until it disappears around 164 K, indicating the ferromagnetic order of etched Cr<sub>5</sub>Te<sub>8</sub>. Additionally, the first-order derivative of *M*–*T* in the inset reveals a magnetic phase transition from paramagnetic to ferromagnetic at *T*<sub>C</sub> = 164 K. The *T*<sub>C</sub> of etched Cr<sub>5</sub>Te<sub>8</sub> is slightly lower than the 176 K of unetched 2D Cr<sub>5</sub>Te<sub>8</sub>,<sup>21</sup> likely due to an increase in atomic defects induced by etching. Further confirmation of ferromagnetism was obtained from the *M*–*H* curves. Figure 4b displays the *M*–*H* curves at various temperatures under an external field perpendicular to the *ab*-plane. The ferromagnetism of etched Cr<sub>5</sub>Te<sub>8</sub> is evident from the *M*–*H* hysteresis loops at 2 and 100 K. Interestingly, the ferromagnetism of etched Cr<sub>5</sub>Te<sub>8</sub> is temperature-sensitive, indicated by the shrinking size of hysteresis loops with increasing temperature. Notably, the saturated magnetic field of etched Cr<sub>5</sub>Te<sub>8</sub> is significantly enhanced compared to that of pristine Cr<sub>5</sub>Te<sub>8</sub>. At 2 K, the saturated magnetic field for etched Cr<sub>5</sub>Te<sub>8</sub> is considerably increased to 38.5 kOe, while pristine Cr<sub>5</sub>Te<sub>8</sub> under the same testing conditions exhibits a saturated magnetic field of only 12 kOe, as shown in Figure 4d.<sup>21</sup> Additionally, the coercivity of etched Cr<sub>5</sub>Te<sub>8</sub> is also enhanced compared to that of pristine Cr<sub>5</sub>Te<sub>8</sub>. The comparison of the coercivity and saturation field between etched Cr<sub>5</sub>Te<sub>8</sub> and pristine Cr<sub>5</sub>Te<sub>8</sub> at different temperatures is depicted in Figure 4c.

The increased coercivity and saturated magnetic field in etched Cr<sub>5</sub>Te<sub>8</sub> may arise from the larger edge-to-area ratio, which strengthens the reentrant stray field of the saturated magnetic domains. For unetched 2D Cr<sub>5</sub>Te<sub>8</sub> nanosheets, labyrinthine magnetic domains spontaneously form in the absence of external fields below the *T*<sub>C</sub>. Upon increasing the applied magnetic field, these domains progressively transition into saturated single domains. At magnetic saturation, a reentrant stray field emerges externally, with maximal magnetic signal intensity observed at the nanosheet edges, where discontinuities in magnetization and thickness occur, contrasting sharply with minimal signals in central regions.<sup>21</sup> This magnetic configuration bears striking similarity to cleaved CrCl<sub>3</sub> flakes.<sup>38</sup> Their MFM studies revealed inhomogeneous single-domain states under saturating fields, characterized by attractive magnetic interactions within the flake interiors and repulsive forces along the peripheries. These observations confirm perpendicular magnetization alignment under external fields, generating reentrant stray fields that peak at structural discontinuities (e.g., edges) while diminishing in uniform bulk regions, analogous to the theoretical prediction that infinite magnetic planes produce no stray fields.<sup>39</sup>

Building upon this framework, we propose that the etched holes in Cr<sub>5</sub>Te<sub>8</sub> nanosheets fundamentally alter the magnetic configuration by increasing the edge-to-area ratio. This geometric modification amplifies reentrant stray field contributions through two mechanisms: (i) introducing additional magnetization discontinuity sites at hole peripheries and (ii)

fragmenting the nanosheet into smaller effective domains. Consequently, higher external magnetic fields become necessary to overcome the intensified stray field interactions and achieve full magnetization saturation. Similar magnetic behavior also appeared in etched MoS<sub>2</sub>, where the increasing edge length resulted in a higher total magnetic moment and significantly enhanced saturation magnetization than that of unetched flakes.<sup>37</sup> Although a quantitative comparison of the saturation magnetization is difficult due to variations in nanosheet coverage across the substrate, our experiments clearly show significant enhancement in the coercivity and saturated magnetic field of the etched nanosheets. The significantly increased saturated magnetic field in etched Cr<sub>5</sub>Te<sub>8</sub> provides a new perspective for controlling the magnetism of 2D materials and studying the evolution mechanism of magnetic domains in 2D materials.

## CONCLUSIONS

In conclusion, we have studied the anisotropic etching process of Cr<sub>5</sub>Te<sub>8</sub> nanosheets. Cr<sub>5</sub>Te<sub>8</sub> nanosheets exhibiting various etched hole patterns, including triangular and hexagonal shapes, were successfully synthesized under excess Te precursor by the CVD method. To the best of our knowledge, this is the first report of anisotropic etching in 2D Cr<sub>5</sub>Te<sub>8</sub>. By tuning the amount of Te precursors, Cr<sub>5</sub>Te<sub>8</sub> nanosheets were etched into nanoribbons. The etching process of Cr<sub>5</sub>Te<sub>8</sub> nanosheets involves two pathways: initiation from the surface and from the edge. Remarkably, the etched Cr<sub>5</sub>Te<sub>8</sub> nanosheets exhibit an enhanced saturated magnetic field, which is up to 3.2 times that of the intact nanosheets and is likely attributed to the increased edge proportion, which strengthens the reentrant stray field of the saturated magnetic domains. This investigation offers critical insights into the multifaceted etching behavior of Cr<sub>5</sub>Te<sub>8</sub>, unveiling a novel approach for manipulating the magnetism of 2D materials.

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## Notes

The authors declare no competing financial interest.

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